

PER361A 7STARLAKE SYSTEM Reliability/Environment Test Plan

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Version History			
Document Release	Date	Change Item	Remarks
V1.0	1/10/2018	Preliminary release	



	System Configuration
Motherboard	OXY5361A3
CPU	Intel [®] Core [™] i3-6100U Processor 2.3 GHz
Memory	innodisk 8GB DDR4 2133 SODIMM M4S0-8GSSO5RG-D26
SATA port1	innodisk SATA SSD 3MG2-P ATA 64GB
LAN1	Intel® I219 GbE LAN
LAN2	Intel® I210 GbE LAN
LAN3	MT321_Intel® I210 GbE LAN
LAN4	MT321_Intel® I210 GbE LAN

	System Test Items Configuration _ Test Results Definition				
No	The data and the second s	Otri	S	ystem Sample	
INO.	Test Rem	Qıy	No.1	Remark	
1.	DC Input Voltage Fluctuation Test	1	PASS		
2.	IO Function Test	1	PASS		
3.	Operation System & Drivers Test	1	PASS		
4.	Power Consumption	1	PASS		
5.	I/O Integrated Stress Test	1	PASS		
6.	Temperature Alternate Operation Test	1	PASS		
7.	High Temperature Operating Test	1	PASS		
8.	High Temperature and Humidity Operating Test	1	PASS		
9.	Low Temperature Operation Test	1	PASS		
10.	High Temperature Power ON/OFF Test	1	PASS		
11	Low Temperature Power ON/OFF Test	1	PASS		
12	Thermal Measurement	1	PASS		



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1. DC Inpu	it Voltage Fluctuation Test		
Test Purpose	To evaluate the influence on the EUT under voltage fluctuation from the DC power Source	Test Result	PASS
Test	DC power source: GW INSTEK PSW 80-27 720W		
Equipment	Passmark USB3.0 Plug 、 COM Loopback		
Quantity Tested	Minimum 1 Set		
Test Condition	Test Software: Passmark BURN-IN Test Program under Microsoft Window Test Procedure: 1. Adjust DC power source to upper limit (VDC+5%) 2. Turn on the system and perform the function test with 10 of 1 hour at least	ws 10 00% loading fo	r a period
	3. Check the functions of the system and record it4. Change DC power source to lower limit (VDC-5%)5. Repeat steps 2~3		
Test Criteria	All units must be pass 1 hour Burn-In test program, without EUT must be no damage or safety problem occurred.	t any error occu	r. The
Test Log / Photo	<complex-block></complex-block>		



2. IO Function Test

Item		Criteria	Result	Note
SATA Port 1		SATAIII Onboard SSD device Run PassMark 20 minutes with all disks	Pass	
COM1 (RS-232)		 Physical Pin define testing (RS232/422/485) (Pcom pro V2.1\ SeaCOM_v030602) Handshaking test (Pcom pro V2.1\ SeaCOM_v030602) Baud rate testing (RS232/422/485) (BEAR UART card) Cable Length testing (232: 15M) 	Pass	
USB2 0 VA		can use any USB device	Pass	
0505.074		Loopback Plugs for USB 3.0 Trouble shooting and Testing	Pass	
		can use any USB device	Pass	
USB2.0 X2		Loopback Plugs for USB 2.0 Trouble shooting and Testing	Pass	
Display output	DP1	Connect Division port monitor division function well	Pass	
Display output	DP2	Connect Display port monitor, display function wen	Pass	
LAN port1		Intel I219 LAN Function Test	Pass	
LAN port2		Intel I210 LAN Function Test	Pass	
LAN port3		Intel I210 LAN Function Test	Pass	
LAN port4		Intel I210 LAN Function Test	Pass	
Power button		Check work well	Pass	
Power Led		Check work well	Pass	
HDD Led		Check work well	Pass	
DC in		Check work well	Pass	



3.Operation System & Drivers Test

Publisher	Package & Version	DUT-1	Note
Microsoft OS	DOS6.22 \ DOS98	Pass	
Microsoft OS	Microsoft Windows 10 Professional 64Bit	Pass	

Driver and Application software	Version / Details	DUT-1	Note
INF	Intel INF 10.1.1.42	Pass	
VGA	Intel HD Graphics 520 ,21.20.16.4627 2017/3/9	Pass	
Audio	Realtek Audio :6.0.1.8036 2017/1/5	Pass	
LAN I219:12.15.23.9 2016/10/26 I210:12.15.184.0 2016/12/8	I219:12.15.23.9 2016/10/26	Pass	
	I210:12.15.184.0 2016/12/8	Pass	



4. Power Consumption

Test Purpose	To measure power consumption of the EUT during operation/suspend mode/power off mode
Quantity Tested	Minimum 1 Set
Test Procedure	 Turn on the power source and set the output voltage frequency following to the test specification Connect the Power Meter between EUT and power source Connect maximum quantity of external devices on all I/O (ex. USB, COM, etc), and have the full loading status on each device Turn on the EUT and set the EUT on each consumption mode Measure and record the power consumption value shown on Power Meter as Watt
Test Criteria	 The Max. power consumption value must not exceed the output ability of used power supply, the derating while in high temperature environment must also to be considered By following the EuP LOT 6 requirement, the power consumption of the standby mode is limited 1.0 Watt (for w/o WOL model) and 1.7Watt (for w/ WOL model)

Item	Device Information (Full load)	
CPU	Intel® Core TM i3-6100U Processor 2.3 GHz	
Memory	innodisk 8GB DDR4 2133 SODIMM M4S0-8GSSO5RG-D26	
SATA port 1	innodisk SATA SSD 3MG2-P 64GB	
DP	Dell U2312	
COM1	COM Loopback	
LAN1 ~ LAN4	LAN (Loopback)	
USB1、USB2	USB KB/Mouse	
USB3~USB6	水泥電阻 1A	
Operating System	Windows 10 Professional 64-bit	
Test Equipment	GW INSTEK PSW 80-27 720W PROVA 11_AC/DC mA clamp meter Agilent U1252B	
Test Software	Burnin test v8.0 × AS SSD × IntelBurnTest 1.9 GaBench v1.32 × SeaCOM_v030602	

Model	Test Voltage	Voltage	Current	Power consumption	
i3-6100U	12 V	11.94 V	4.26 A	50.86 W	
	9V	8.91V	5.91A	52.65 W	
	36V	35.9V	1.49A	53.49 W	



Item	Device Information (Heavy load)
CPU	Intel® Core TM i3-6100U Processor 2.3 GHz
Memory	innodisk 8GB DDR4 2133 SODIMM M4S0-8GSSO5RG-D26
SATA port 1	innodisk SATA SSD 3MG2-P ATA 64GB
DP	Dell U2312
COM1	N/A
LAN1 ~ LAN4	N/A
USB1 v USB2	USB KB/Mouse
USB3~USB6	N/A
Operating System	Windows 10 Professional 64-bit
Test Equipment	GW INSTEK PSW 80-27 720W PROVA 11_AC/DC mA clamp meter Agilent U1252B
Test Software	Burnin test v8.0 、

Power Measure (Heavy load)								
Model	Voltage	Voltage	Idle	S 3	S4	S5	Current	Power consumption
i3-6100U	12 V	11.94 V	0.67A	0.41 A	0.35 A	0.34 A	2.2 A	26.268W



5. I/O Integrated Stress Test

System configu	ration							
CPU		Intel® Core™ i3-6100U Processor 2.3 GHz						
RAM1		innodisk 8GB DDR4 2133 SODIMM M4S0-8GSSO5RG-D26						
SATA port 1		innodisk SATA SSD 3MG2-P ATA 64GB						
O.S.		Windows 10 64bit						
Temperature		Room temperature						
Testing Utility a	and preference							
Test Software		Test Preference	Test Time(Hours)	Result	Note			
PASSMARK BrunIn test (8.0)		Reference below setting	ence below setting 12 PASS					
Test item	Loading (%)	Test preference	Test preference					
CPU	100	Default preference: Select CPU test types: General purpose instructions, Floating Point Unit instructions, Prime number test Extension instructions: MMX, 3DNow!, SSE, SSE2 CPU affinity: Normal task scheduling						
RAM	100	Default preference: RAM test mode and test pattern: Standard Test: Default(Cyclic)						
Com Port(s)	100	Default preference: Detect and loopback test Send and receive timeout: 3500 Port speed: 115200 Kbits/Sec	Default preference: Detect and loopback test Send and receive timeout: 3500 Port speed: 115200 Kbits/Sec					
Video	100	Default preference: Select video playback files: C:\\Clock.avi						
2D Graphics	100	Default preference: 2D Graphics Test: All availiable Video Memory						
3D Graphics	100	Default preference: Test window setup (Multiple monitorof testing): Number of: 1(default) Window placement: Auto placement on primary monitor (default) Window size: 300x200 pixels (default)						
LAN port 1	100	LAN port Loopback	LAN port Loopback					
LAN port 2	100	LAN port Loopback						
LAN port 3	100	LAN port Loopback						
LAN port 4	100	LAN port Loopback						

Test photo







6. Temperature Alternate Operation Test





7. High Temperature Operating Test Device Model PER361A Diagram of curves ^



Test Result

PASS

- 1. The connectors and components should work properly without any interference.
- 2. All screws should be tightened up appropriately.



8. High Temperature and Humidity Operating Test



2. All screws should be tightened up appropriately.



9. Low Temperature Operation Test **PER361A Device Model Test Result** PASS **Diagram of curves Test Temperature** Test Time Temp (°C) **∧** Low -40 24Hours 25 Test Reference Standard IEC60068-2 Time (hour) Test Burnin test v8.0 -40 Software 1.5 25.5 27 **Test picture** OXO **Test procedure** 27. This operation test is under temperature range 25° C ~ -40°C 28. Standards is referred to IEC60068-2-1 Change of temperature 29. Have the subject inside the chamber and set up related cables. 30. Set up the temperature 31. If it's OK then rise up temperature to -40°C and run Burnin test v8.0 for stress test 32. Power on test and Perform minimum 3 power on/off cycles (to be sure that subject can reboot) 33. Observe the temperature and the subject in the test execution 34. Check the damage on the subject by visual and do function test Note: **Electronic function check:** 1. All system functions must be checked with appropriate testing programs and should pass the inspection. 2. Running Windows for OS, the system should not have degradation in its performance. Mechanical function check: 1. The connectors and components should work properly without any interference.

2. All screws should be tightened up appropriately.



10. High Temperature Power ON/OFF Test





11. Low Temperature Power ON/OFF Test





12. Thermal Measurement

Test Purpose	The purpose of performing thermal profile test is to identify potential thermal problem of the EUT. And it is to aid products in reliability assessment considering that semiconductor failure rates rise rapidly with increasing junction temperature In case of systems cooling, patterns will vary with stacking choices, temperature/thermal mapping can aid in the development of optimum tacking arrangements						
Test Equipment	KSON THS-B4T-150 Chamber YOKOGAWA MV1000, Thermometer (FLUKE50D K/J) Infrared thermal imaging camera Model TVS-200EX						
Quantity Tested	Minimum 1 Set						
Test Software	Passmark Burn-In Test under Windows 10						
Test Procecedure	 Thermal pre-scan measurement: Temperature: 24~26°C/40~60%RH Capture thermal IR photo for whole boards after the EUT execute passmark burn-in test with 100% lading during 1 hour at least. Thermal actual measurement: a. Select the test points according to the IR photo and attach thermocouples to the hot points b. Put the EUT in thermal chamber and set the temperature profile of as test specification c. Turn on the thermal chamber and power on the EUT to enter windows environment to run Max Power Test + 3DMARK 2003 application program d. After the EUT executing the test software for 4 hours, record thermal maximum value for each thermocouples point. e. Turn off the thermal chamber and EUT f. Verify and check recorded figure of each components to its' operating temperature range listed in specification/approval sheet of each measured component 						
Test diagram of curves	Environment defines for 8 hours 70 60 55 50 40 25 1.5 $3 4.5 5 6.5 8 9.5 10 11.5 12 13.5 14 15.5 16 17.5 18 19.5 (hour)$ -20 -40						
Test picture							



Thermal point













Test Result

Point	-40°C	-20°C	0°C	25℃ Room temperature	50°C	55℃	60° ℃	65 ℃	70°C
CPU Frequency	2.29GHz	2.0GHz	1.9GHz	2.29GHz	2GHz	1.7GHz	1.5GHz	1.5GHz	1.5GHz
CPU T-J	0	5	34	95	97	97	100	100	100
1.CPU Die 1	-35	-8.6	7.3	53.2	66.2	72	75.8	79.5	83.5
2.CPU Die 2	-21	-1.6	18.8	67.1	78	83.4	86.6	91.1	93
3.RAM	-20	2.3	21.7	73.7	86	91.5	96	100	102.8
4.I219	-27.2	-3.8	16.7	60.5	73.6	79	83.2	88	92
5.I210	-25	-2	15	65	80	86	91	94	98
6.CPU 銅片	-33	-12	6.7	53.1	66	71.3	76	80	84.8
7.sink	-40	-16	2.2	44.7	61.2	66.8	71.1	76.6	79
I219 LAN 1000M (Mb)	937	937	936	936	922	937	944	944	944
I219 LAN 100M (Mb)	94.1	94.2	94.1	94	94	94.2	94.2	94.2	94.2
I210-1 LAN 1000M (Mb)	920	923	920	922	926	922	944	944	944
I210-1 LAN 100M (Mb)	83.8	83.6	83.4	83.7	83.6	83	94.2	94.2	94.2
I210-2 LAN 1000M (Mb)	944	945	944	943	944	944	944	944	944
I210-2 LAN 100M (Mb)	90.6	82.9	82.5	90.6	84.6	90.6	82.2	90.6	90.6
I210-3 LAN 1000M (Mb)	945	944	944	943	943	944	944	944	944
I210-3 LAN 100M (Mb)	82.8	81.2	84.7	83.3	87.4	81.8	91.4	94.2	94.2
innodisk 64GB SSD (Read MB)	511MB/S	514MB/S	501MB/S	513MB/S	507MB/S	514MB/S	505MB/S	512/MB/S	516MB/S
innodisk 64GB SSD (Write MB)	193MB/S	193MB/S	194MB/S	196MB/S	196MB/S	196MB/S	197MB/S	197MB/S	196MB/S